

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination CHIN ET AL.	
		10/787,015	Examiner	Art Unit 1651
David M. Naff		Page 1 of 1		

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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